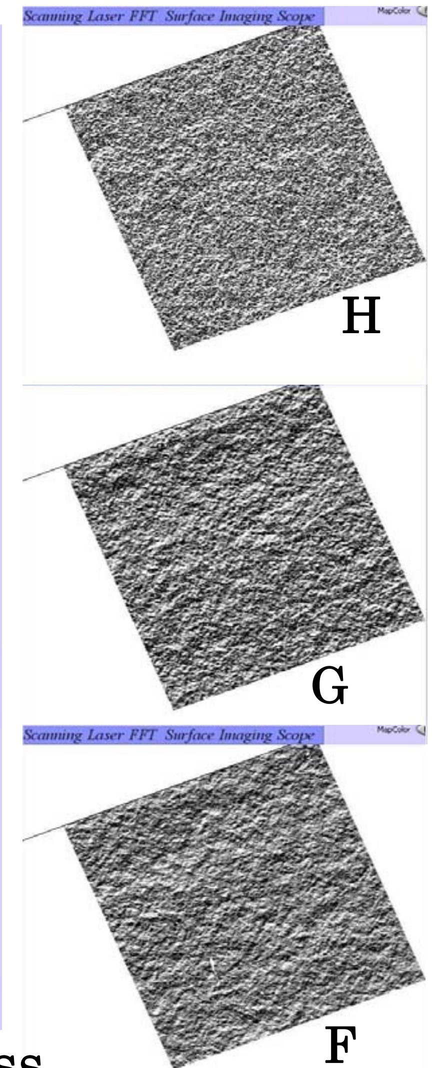
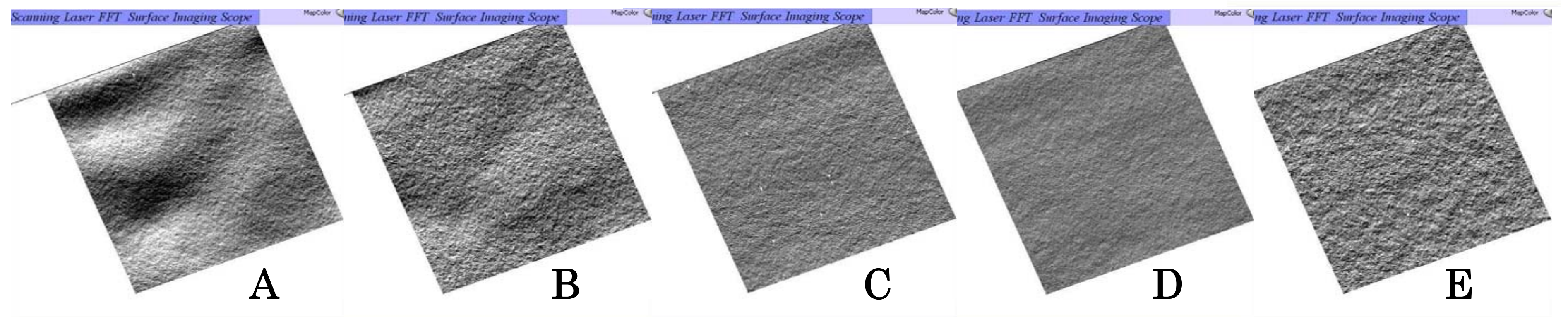
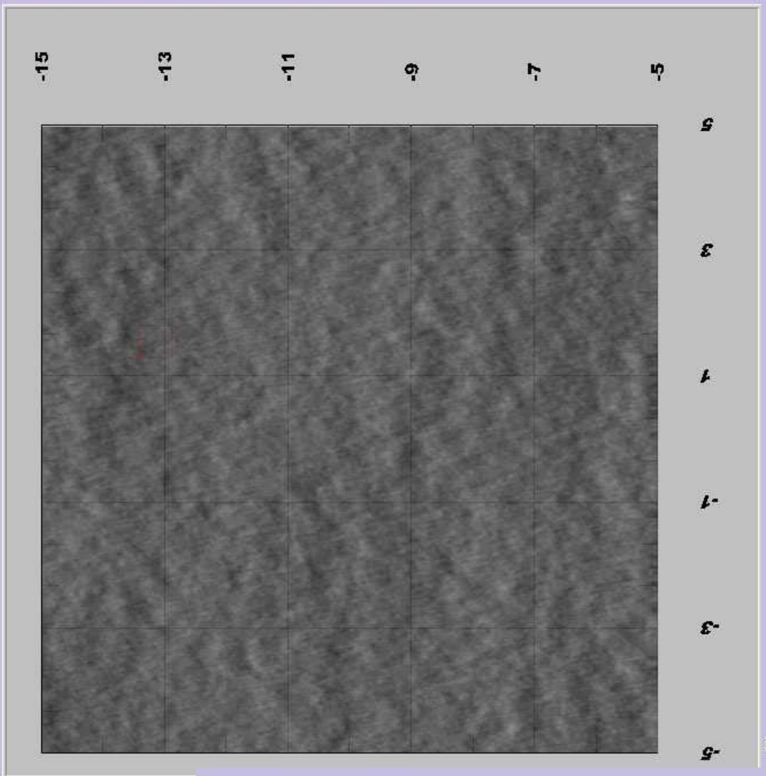
Inspection Area
10x10 mm

Black to white
15 nm



Si wafer surface inspection FFT analyze-comparison process





Black to white
15 nm

Inspection Area
30x30 mm

Si wafer surface analyze
comparison process